Notice of References Cited

Application/Control No. 10/606,410	Applicant(s)/Pater Reexamination MUNRO ET AL.	nt Under
Examiner	Art Unit	
STEVEN B. THERIAULT	2179	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0105532 A1	08-2002	Oblinger, Daniel A.	345/701
*	В	US-2002/0105550 A1	08-2002	Biebesheimer et al.	345/835
*	O	US-2002/0107842 A1	08-2002	Biebesheimer et al.	707/3
*	D	US-2002/0107843 A1	08-2002	Biebesheimer et al.	707/3
*	Е	US-2002/0107852 A1	08-2002	Oblinger, Daniel A.	707/5
*	F	US-2002/0149614 A1	10-2002	Biebesheimer et al.	345/738
*	G	US-2002/0152190 A1	10-2002	Biebesheimer et al.	707/1
*	Н	US-2003/0126235 A1	07-2003	Chandrasekar et al.	709/220
*	_	US-6,778,193 B2	08-2004	Biebesheimer et al.	715/805
*	J	US-2006/0200462 A1	09-2006	Kadayam et al.	707/005
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		l			
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		
	v		
	w		
	x		

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.